

Provided with
TrueDimensions™
Online access to key probe
parameters for every
individual tip



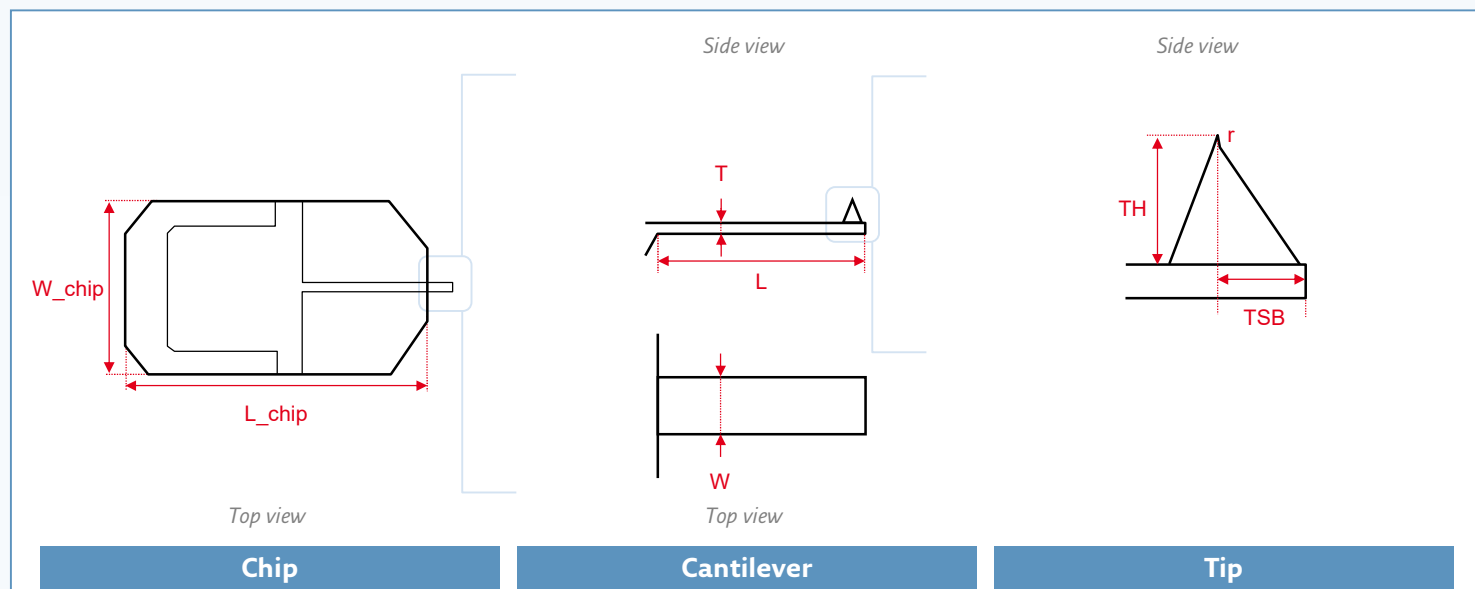
	EBD-RTESPA	EBD-FESPA
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Part number	EBD-RTESPA	EBD-FESPA
Tip		
Material	HDC/DLC	HDC/DLC
Sharpness / r	7 nm	7 nm
Total tip height / TH	15 µm (10-15 µm)	15 µm (10-15 µm)
Tip set back / TSB	15 µm (5-25 µm)	15 µm (5-25 µm)
Cantilever		
Material	Si	Si
Shape	NT-RTESPA	NT-FM
Length / L	120 µm (±5 µm)	225 µm (±25 µm)
Width / W	30 µm (±2 µm)	28 µm (±5 µm)
Thickness / T	4.4 µm (±0.5 µm)	3 µm (±0.5 µm)
Force constant ^[1] / k	40 N/m (±20 N/m)	2.8 N/m (1-5 N/m)
Resonance frequency ^[1] / f	320 kHz (±50 kHz)	75 kHz (±25 kHz)
Tip side coating	none	none
Back side coating	reflex	reflex
Chip		
Length / L_chip	3400 µm	3400 µm
Width / W_chip	1600 µm	1600 µm
Thickness / T_chip	315 µm	315 µm
Alignment grooves	no	yes

- Consistent sharpness
- Diamond-like durability
- Starting at \$60



[1] Resonance frequency f extracted from LDV measurements; cantilever stiffness k calculated from the (measured) cantilever geometry. Actual values of >90% of all probes are guaranteed to be within the specified range.



For more information, visit
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